



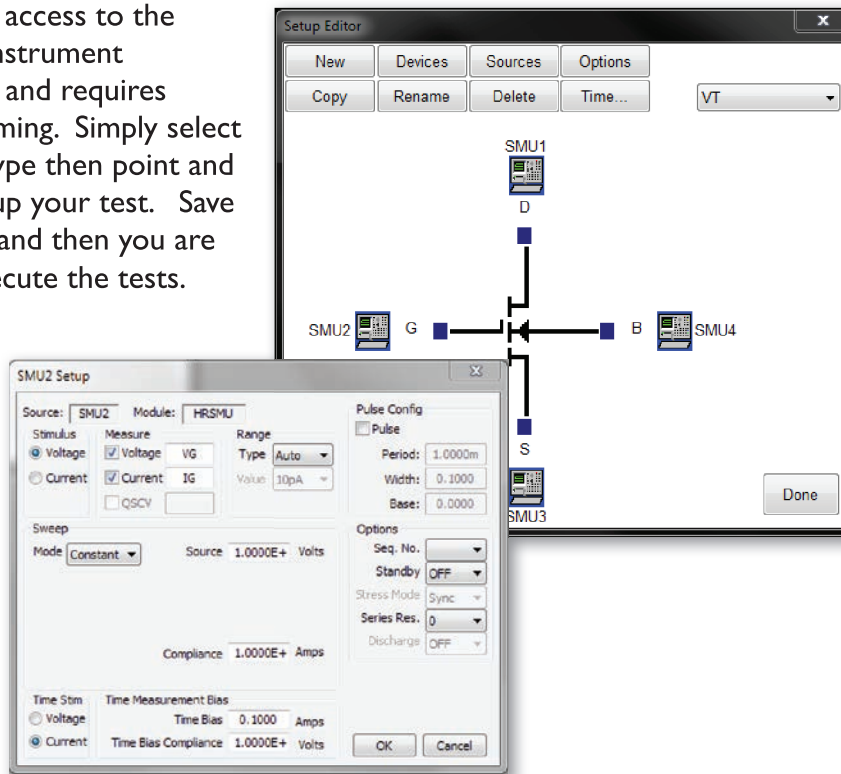
**Point, Click, Measure.**  
*It's as simple as that.*



Metrics ICS software supports all aspects of device characterization, from basic measurements using a test fixture to performing receiving inspection of discrete parts to sequenced measurements using a manual probe to perform process development tasks or failure analysis on wafer.

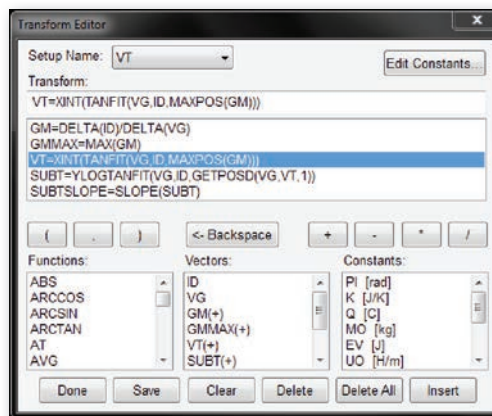
## Graphical Test Generation

Built-in graphical test generation using the test setup editor provides full access to the supported instrument functionality and requires no programming. Simply select the device type then point and click to set up your test. Save the settings and then you are ready to execute the tests.



## Numerical Transform Editor

Specify additional analysis functions using the built-in numerical transform editor to apply lists of equations to the measured data. Included are common numerical operators, line fitting, user-defined constants as well as other specialized functions specific to extracting parameters for semiconductor characteristics.



## Fast and Easy Test Sequencing

Metrics ICS provides a simple way to perform test sequencing without programming. Using the built-in sequence editor you can select existing test setups and then re-arrange the order of defined tests. Once you have saved your project then simply select the sequence measure tool from the measure toolbar to run all the selected tests.

## The Metrics Technology Advantage

### CONTINUITY IN THE LAB

Metrics software allows you to implement a common software interface throughout the lab across multiple vendor's instruments. Your learning curve is greatly reduced because all instruments are presented in a unified and similar manner so you can begin making productive parametric measurements immediately with the latest or legacy equipment and instruments. The use of one software platform to cover a diverse equipment set improves communication and training time is reduced.

### EASE OF USE

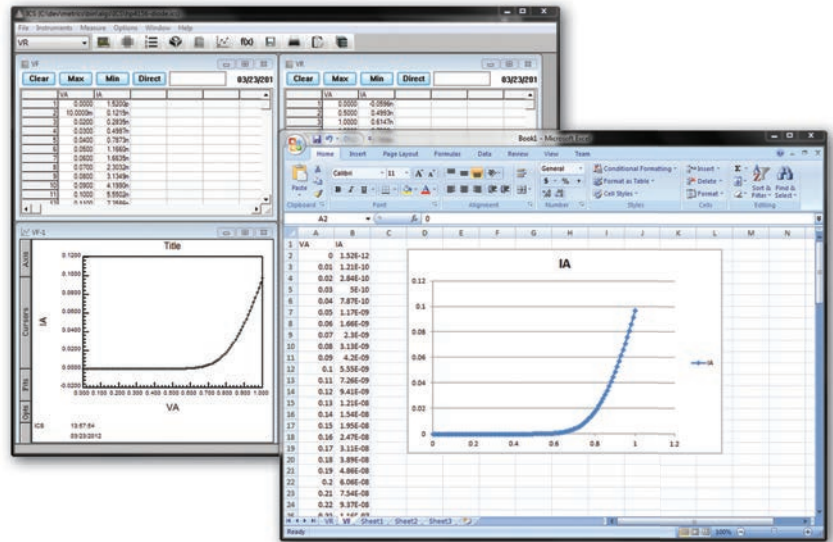
Metrics software provides easy setup for complex instrumentation through an interactive graphical user interface, and requires no programming by the end user. It has a full suite of data analysis tools and provides quick transfer of data to popular software packages. All this capability allows the engineer to focus on testing, not on writing and maintaining custom code.

### DEDICATION

Metrics Technology's products have been created "by engineers for engineers". Our knowledge and products are specific to the semiconductor engineering laboratory. This is why our instrument drivers are more capable and flexible than our competitors. We understand the tests you are performing and the equipment you use. We work to address end-user challenges to create a better software platform. Our business is software and only software. Our products have been an industry standard for more than 20 years and have often been copied, but never duplicated.

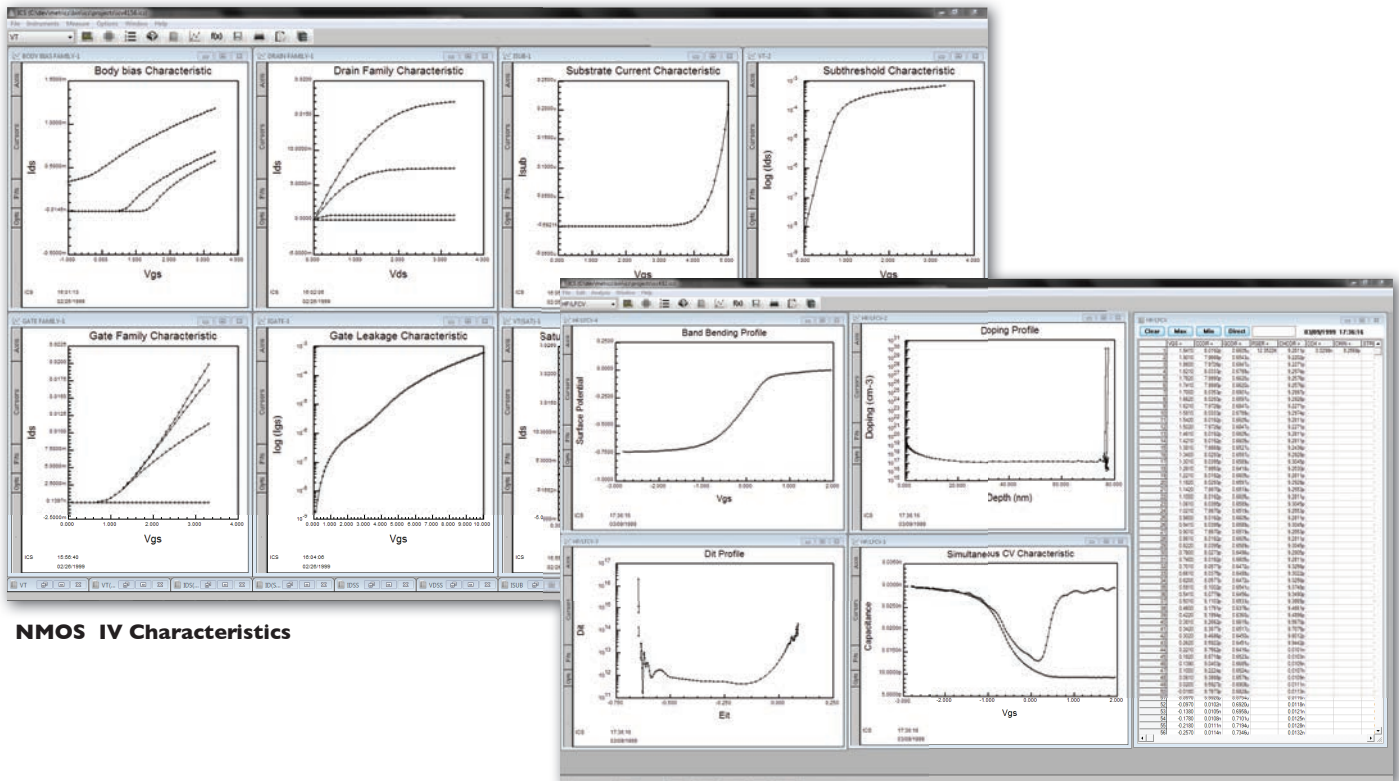
# Automatic Data Collection and Report Generation

Metrics ICS has the ability to automatically synchronize data in real-time with Microsoft Excel. Create user-defined macros in Excel to create automated reports. You can also export comma or tab-delimited ASCII data to be used in other popular software packages such as spreadsheets, word processors, and databases. You can save data to any drive connected to the PC including shared volumes on the local area network.



# Perform IV and CV Testing

You can perform both IV and CV testing with Metrics ICS. Several supported CV instruments have special compensation algorithms to provide support for standard cable length and phase shift compensation. Open, short and load calibration routines are also provided for achieving maximum accuracy.



NMOS IV Characteristics

Simultaneous CV Analysis - (using supported equipment)

